

Edge

The ultimate tool for 300 mm device characterization and reliability test

Edge System (from 1 Hz to 40 MHz)

Edge Module (from 1 Hz to 10 MHz)*

*The Edge module shown with Summit 12000 series probe station including eVue, thermal system and anti-vibration table.

Flicker noise measurement software

- Unattended test execution with user-specified bias conditions
- Controls all instruments and recommends series resistances for flicker noise measurement
- Dynamically calculates system roll-off frequency
- Calculates and sets SMU voltages
- Measures noise parameters
- Extracts 1/f noise model parameters
- Analyzes statistical data
- Creates reports
- Graphically displays results and archives data files
- RTS measurement with time domain function

Noise processing unit

- Process analog to digital signal
- Provides control for noise measurement
- Controls SMU and set biasing condition
- Computes noise data

Compatible with external SMU

- Provides voltage and measurement current to DUT

Signal acquisition unit

- Provides remote load- and source-resistor switching
- Advanced low-leakage SMU filters
- Low-noise amplifier and switchable signal paths for either 1/f or standard DC measurements

Nucleus™ prober control software

- Easy-to-use graphical interface
- Multi-user support
- Extensive on-line support
- Customize your setups

-60°C to 300°C thermal system

- Dedicated power-conditioning module and special filters assure ultra low-noise operation at extended wafer temperatures

eVue™ digital imaging system

- Quickly navigate and setup tests
- View multiple perspectives of a test device simultaneously
- Control probe overdrive for improved data accuracy

MicroChamber®

- Chuck enclosure ensures moisture-free, light-tight, EMI protected measurements, making over-temperature measurements easy

Safe wafer loading and unloading

- Full-wafer access, via locking, roll-out stage

Integrated thermal chuck

- Fully integrated, electrically quiet, guarded, thermal chuck heats or cools wafer

Low-noise 300 mm wafer prober

- Unprecedented stepping accuracy and wafer planarity over the full temperature range

Small-footprint, fully integrated system

- Built-in components include motion control, computer controller, anti-vibration and air-management systems

Racked test instruments

- Houses DC parametric analyzer, power-conditioning module



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